

July 2012

FDMS7670

N-Channel PowerTrench® MOSFET 30 V, 3.8 m Ω

Features

- Max $r_{DS(on)} = 3.8 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 21 \text{ A}$
- Max $r_{DS(on)} = 5.0 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 17 \text{ A}$
- Advanced Package and Silicon design for low r_{DS(on)} and high efficiency
- Next generation enhanced body diode technology, engineered for soft recovery. Provides Schottky-like performance with minimum EMI in sync buck converter applications
- MSL1 robust package design
- 100% UIL tested
- RoHS Compliant

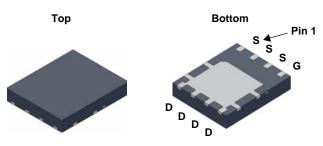


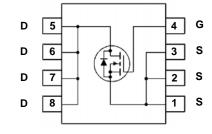
General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency and to minimize switch node ringing of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{\rm DS(on)}$, fast switching speed and body diode reverse recovery performance.

Applications

- IMVP Vcore Switching for Notebook
- VRM Vcore Switching for Desktop and Server
- OringFET / Load Switch
- DC-DC Conversion





Power 56

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter	Parameter			Units
V_{DS}	Drain to Source Voltage			30	V
V_{GS}	Gate to Source Voltage		(Note 4)	±20	V
	Drain Current -Continuous (Package limited)	T _C = 25 °C		42	
I _D	-Continuous (Silicon limited) T _C =			105	_
	-Continuous	T _A = 25 °C	(Note 1a)	21	Α
	-Pulsed			150	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	144	mJ
Power Dissipation		T _C = 25 °C		62	W
P_D	Power Dissipation	T _A = 25 °C	(Note 1a)	2.5	VV
T _J , T _{STG}	Operating and Storage Junction Temperature R	ange		-55 to +150	°C

Thermal Characteristics

$R_{ heta JC}$	Thermal Resistance, Junction to Case		2.0	0C/M
$R_{\theta,IA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS7670	FDMS7670	Power 56	13 "	12 mm	3000 units

Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		15		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.25	1.9	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		-7		mV/°C
		V _{GS} = 10 V, I _D = 21 A		2.9	3.8	
r _{DS(on)}		$V_{GS} = 4.5 \text{ V}, I_D = 17 \text{ A}$		4.1	5.0	mΩ
		$V_{GS} = 10 \text{ V}, I_D = 21 \text{ A}, T_J = 125 \text{ °C}$		4.0	5.3	
9 _{FS}	Forward Transconductance	V _{DS} = 5 V, I _D = 21 A		136		S

Dynamic Characteristics

C _{iss}	Input Capacitance	45.77.7	3085	4105	pF
C _{oss}	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	990	1315	pF
C _{rss}	Reverse Transfer Capacitance	1 – 1 101112	75	115	pF
R _a	Gate Resistance		1.2	2.5	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		15	26	ns
t _r	Rise Time	V _{DD} = 15 V, I _D = 21 A,	6	12	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	31	50	ns
t _f	Fall Time		5	10	ns
Q_g	Total Gate Charge	V _{GS} = 0 V to 10 V	40	56	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ $V_{DD} = 15 \text{ V}$,	17	24	nC
Q _{gs}	Gate to Source Charge	I _D = 21 A	9.8		nC
Q_{gd}	Gate to Drain "Miller" Charge		4.4		nC

Drain-Source Diode Characteristics

Source to Drain Diade Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.1 \text{ A}$ (Note 2)	0.7	0.95	V
Source to Drain Diode Polward Voltage	V _{GS} = 0 V, I _S = 21 A (Note 2)	0.8	1.1	V
Reverse Recovery Time		38	61	ns
Reverse Recovery Charge		19	34	nC
Reverse Recovery Fall Time	I _F = 21 A, di/dt = 100 A/μs	14		ns
Reverse Recovery Rise Time		24		ns
Softness (t _b /t _a)		1.7		
Reverse Recovery Time	1 21 A di/dt 200 A/v.a	32	51	ns
Reverse Recovery Charge	1F = 21 A, αι/αι = 300 A/μs	34	54	nC
	Reverse Recovery Charge Reverse Recovery Fall Time Reverse Recovery Rise Time Softness (t _b /t _a) Reverse Recovery Time	Source to Drain Diode Forward Voltage $V_{QS} = 0 \text{ V}, I_S = 21 \text{ A}$ (Note 2) Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Fall Time $V_{QS} = 0 \text{ V}, I_S = 21 \text{ A}$ (Note 2) Reverse Recovery Fall Time $V_{QS} = 0 \text{ V}, I_S = 21 \text{ A}$ (Note 2) Reverse Recovery Fall Time $V_{QS} = 0 \text{ V}, I_S = 21 \text{ A}$ (Note 2)	Source to Drain Diode Forward Voltage $V_{GS} = 0 \text{ V}, V_{IS} = 21 \text{ A}$ (Note 2) 0.8 Reverse Recovery Time 38 Reverse Recovery Charge 19 Reverse Recovery Fall Time 14 Reverse Recovery Rise Time 24 Softness (t_b/t_a) 1.7 Reverse Recovery Time 15 Reverse Recovery Time 17 Reverse Recovery Time 17 $V_{GS} = 0 \text{ V}, V_{IS} = 21 \text{ A}$ (Note 2) 0.8	Source to Drain Diode Forward Voltage $V_{GS} = 0 \text{ V}, I_S = 21 \text{ A}$ (Note 2) 0.8 1.1 Reverse Recovery Time 38 61 Reverse Recovery Charge 19 34 Reverse Recovery Fall Time $I_F = 21 \text{ A}, \text{ di/dt} = 100 \text{ A/µs}$ 1.7 Reverse Recovery Time 24 Softness (t_b/t_a) 1.7 Reverse Recovery Time 32 51

^{1.} $R_{\theta,JA}$ is determined with the device mounted on a 1 in 2 pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta,JC}$ is guaranteed by design while $R_{\theta,CA}$ is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 125 °C/W when mounted on $\,a\,$ minimum pad of 2 oz copper.

^{2.} Pulse Test: Pulse Width < 300 $\mu\text{s},$ Duty cycle < 2.0%.

^{3.} E_{AS} of 144 mJ is based on starting $T_J = 25$ °C, L = 1 mH, $I_{AS} = 17$ A, $V_{DD} = 27$ V, $V_{GS} = 10$ V. 100% test at L = 0.3 mH, $I_{AS} = 22$ A.

^{4.} As an N-ch device, the negative Vgs rating is for low duty cycle pulse occurrence only. No continuous rating is implied.

©2012 Fairchild Semiconductor Corporation

2

Typical Characteristics $T_J = 25$ °C unless otherwise noted

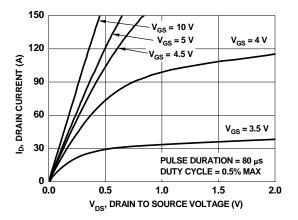


Figure 1. On Region Characteristics

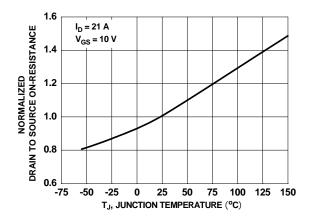


Figure 3. Normalized On Resistance vs Junction Temperature

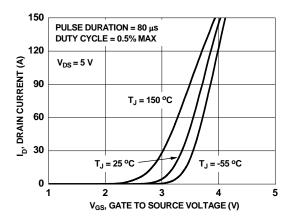


Figure 5. Transfer Characteristics

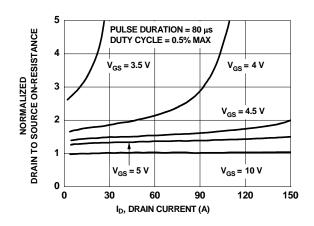


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

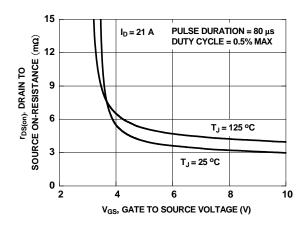


Figure 4. On-Resistance vs Gate to Source Voltage

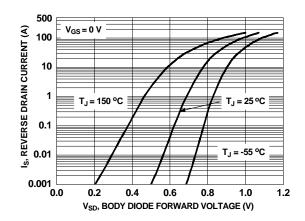


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25$ °C unless otherwise noted

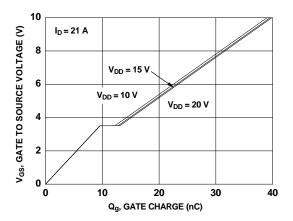


Figure 7. Gate Charge Characteristics

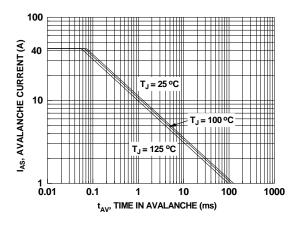


Figure 9. Unclamped Inductive Switching Capability

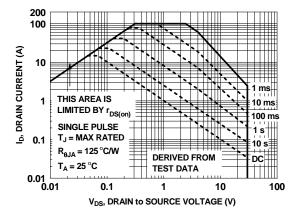


Figure 11. Forward Bias Safe Operating Area

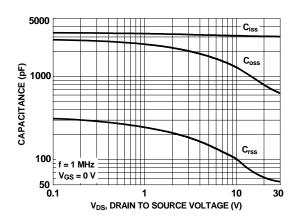


Figure 8. Capacitance vs Drain to Source Voltage

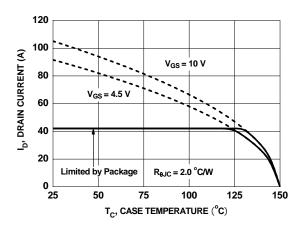


Figure 10. Maximum Continuous Drain Current vs Case Temperature

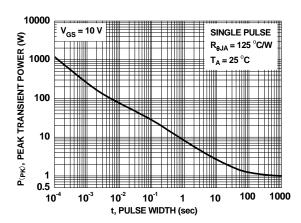


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25$ °C unless otherwise noted

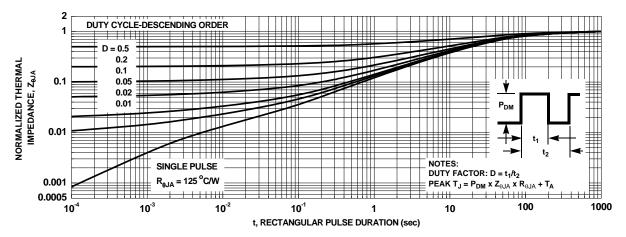


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

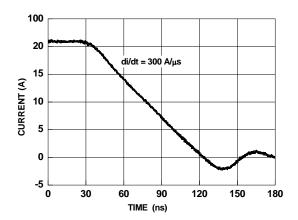
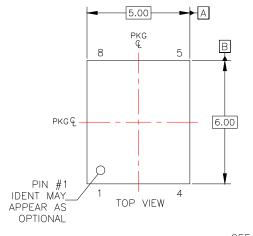
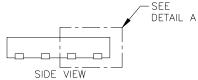
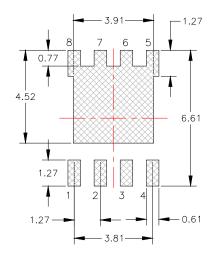


Figure 14. Body Diode Reverse Recovery Characteristics

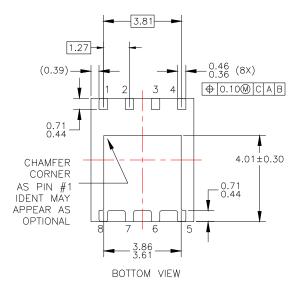
Dimensional Outline and Pad Layout

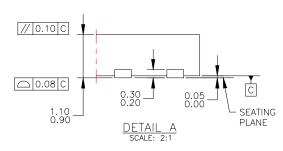


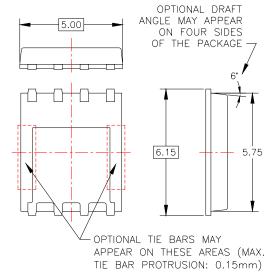




LAND PATTERN RECOMMENDATION







NOTES: UNLESS OTHERWISE SPECIFIED

- PACKAGE STANDARD REFERENCE:
 JEDEC MO-240, ISSUE A, VAR. AA,
 DATED OCTOBER 2002.
 ALL DIMENSIONS ARE IN MILLIMETERS.
 DIMENSIONS DO NOT INCLUDE BURRS
 OR MOLD FLASH. MOLD FLASH OR
 BURRS DOES NOT EXCEED 0.10MM.
 DIMENSIONING AND TOLERANCING PER
 ASME Y14.5M-1994.
 DRAWING FILE NAME: POFNO8AREV4





TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

2Cool™ F-PESTM PowerTrench[®] FRFFT® AccuPower™ PowerXSTM

AX-CAP^{TM*}
BitSiC[®] Global Power ResourceSM Programmable Active Droop™ Green Bridge™ QFET®

Build it Now™ Green FPS™ QSTM Green FPS™ e-Series™ CorePLUS™ Quiet Series™ CorePOWER™ RapidConfigure™

G*max*™ GTO™ CROSSVOLT™ IntelliMAX™ Current Transfer Logic™ ISOPLANAR™ Saving our world, 1mW/W/kW at a time™

DEUXPEED® Marking Small Speakers Sound Louder SignalWise™ Dual Cool™ and Better™ SmartMax™ EcoSPARK[®] MegaBuck™ SMART START™

EfficentMax™ MICROCOUPLER™ Solutions for Your Success™ ESBC™ MicroFET™

MicroPak™ STEALTH™ MicroPak2™ SuperFET® MillerDrive™ SuperSOT™-3 MotionMax™ SuperSOT™-6 SuperSOT™-8 Motion-SPM™ SupreMOS® mWSaver™

FACT® FAST® OptoHiT™ . SyncFET™ OPTOLOGIC® Sync-Lock™ FastvCore™ **OPTOPLANAR®** FETBench™ FlashWriter® *

*Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

The Power Franchise®

TinyBoost™ TinyBuck™ TinyCalc™ TinyLogic[®] TINYOPTO™ TinvPower™ TinyPWM™ TinyWire™ TranSiC®

TriFault Detect™ TRUECURRENT®* uSerDes™

UHC® Ultra FRFET™ UniFET™ VCX™ VisualMax™ VoltagePlus™ XSTM

Fairchild[®]

Fairchild Semiconductor®

FACT Quiet Series™

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY
FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

- Life support devices or systems are devices or systems which (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information Formative / In Design		Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete Not In Production		Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. I61